

### **Description**

The AP150N03D uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = 30V I_{D} = 150A$ 

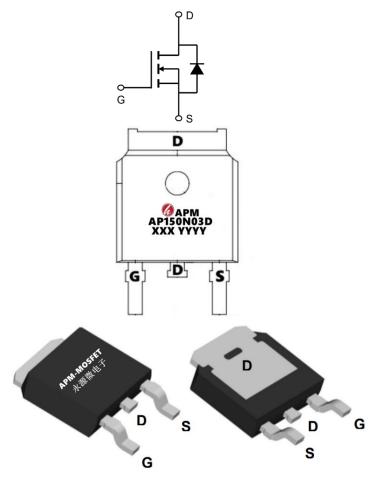
 $R_{DS(ON)} < 3.0 \text{m}\Omega$  @  $V_{GS} = 10 \text{V}$  (Type: 2.2 m $\Omega$ )

#### **Application**

Battery protection

Load switch

Uninterruptible power supply



**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
AP150N03D	TO-252-3	AP150N03D XXX YYYY	2500

### Absolute Maximum Ratings (TC=25°C unless otherwise specified)

Symbol	Parameter	Rating	Units	
VDS	Drain-Source Voltage	30	V	
VGS	Gate-Source Voltage	±20	V	
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	155	А	
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	110	А	
IDM	Pulsed Drain Current <sup>2</sup>	310	Α	
EAS	Single Pulse Avalanche Energy <sup>3</sup>	246	mJ	
IAS	Avalanche Current	48	Α	
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	89.3	W	
TSTG	STG Storage Temperature Range		°C	
TJ	T <sub>J</sub> Operating Junction Temperature Range -55 to		°C	
R <sub>θ</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>	62	°C/W	
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	1.4	°C/W	





## **AP150N03D**

## **30V N-Channel Enhancement Mode MOSFET**

### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30	36		V	
∆BVDSS/∆TJ	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.022		V/°C	
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =30A		2.2	3.0	mΩ	
ND3(ON)	Static Drain-Source On-Ivesistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		3.2	4.0	11122	
VGS(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2	1.7	2.5	V	
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS, ID -2000A		-6.1		mV/°C	
IDSS	Drain Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA	
ספטו	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			10	uA	
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA	
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =30A		60		S	
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		0.9		Ω	
Qg	Total Gate Charge (4.5V)			56.9			
Qgs	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =10V , I <sub>D</sub> =15A		13.8		nC	
Qgd	Gate-Drain Charge			23.5			
Td(on)	Turn-On Delay Time			20.1			
Tr	Rise Time	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V ,		6.3		]	
Td(off)	Turn-Off Delay Time	$R_G=3.3\Omega$ , $I_D=1A$		124.6		ns	
T <sub>f</sub>	Fall Time			15.8			
Ciss	Input Capacitance			5935			
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		725		pF	
Crss	Reverse Transfer Capacitance			538			
IS	Continuous Source Current <sup>1,5</sup>	V V 0V 5			155	Α	
ISM	Pulsed Source Current <sup>2,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			310	Α	
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =A , T <sub>J</sub> =25°C			1.2	V	

#### Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- $2_{\times}$  The data tested by pulsed , pulse width  $\leqq 300 us$  , duty cycle  $\leqq 2\%$
- $3\$  The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1Mh,IAS=48A
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



#### **Typical Characteristics**

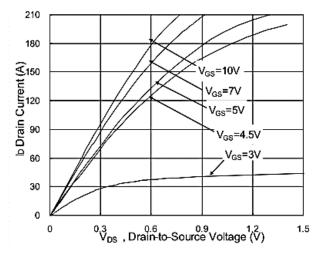


Fig.1 Typical Output Characteristics

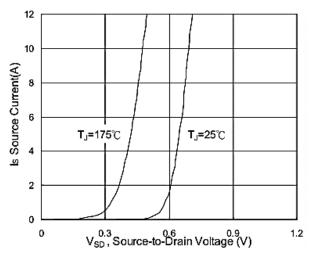


Fig.3 Forward Characteristics of Reverse

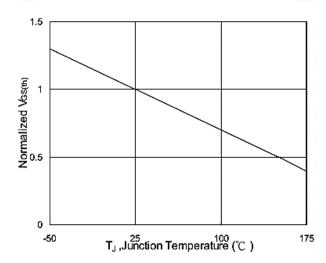


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

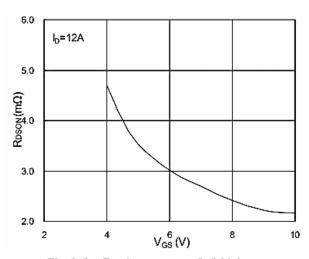


Fig.2 On-Resistance vs. G-S Voltage

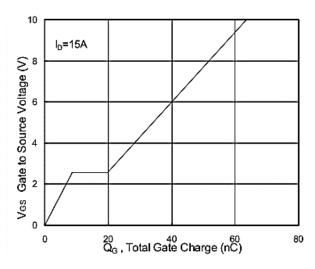


Fig.4 Gate-Charge Characteristics

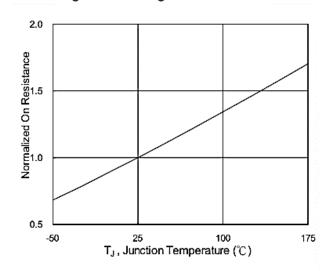
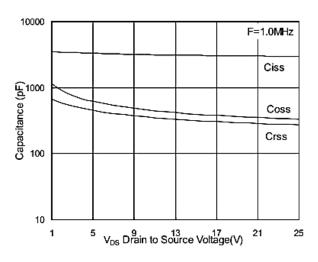


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>







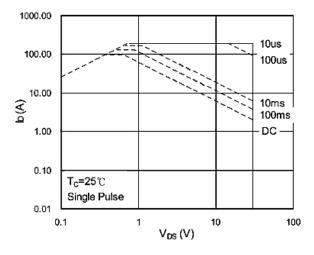


Fig.7 Capacitance

Fig.8 Safe Operating Area

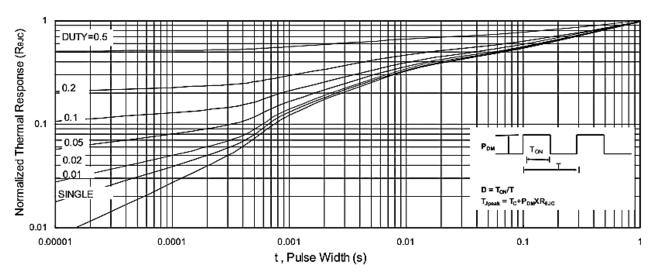


Fig.9 Normalized Maximum Transient Thermal Impedance

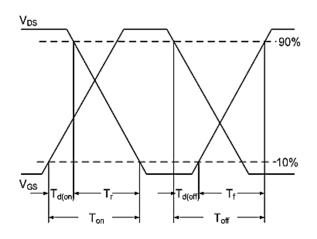


Fig.10 Switching Time Waveform

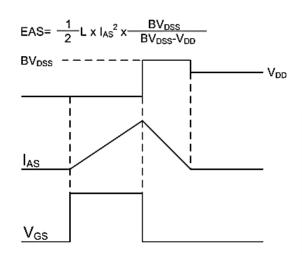
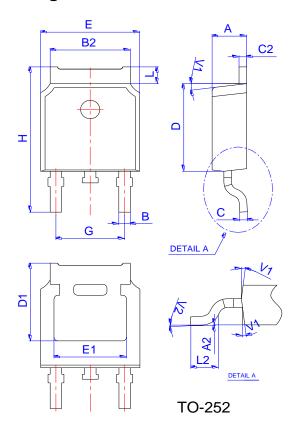


Fig.11 Unclamped Inductive Switching Waveform

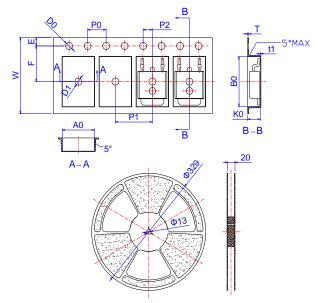


## Package Mechanical Data: TO-252-3L



	Dimensions					
Ref.		Millimeters		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

## **Reel Spectification-TO-252**



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



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#### 30V N-Channel Enhancement Mode MOSFET

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# **AP150N03D**

## **30V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
REV3.8	2020/5/1	Initial release
REV3.9	2023/4/15	Reduce internal RDS

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